

Method for inspecting an integrated circuit.

The method for inspecting an integrated circuit comprising a plurality of sub-circuits includes the determination of the supply current into at least one of the sub-circuits. This supply current is determined, while the other sub-circuits are operational, by measuring the voltage over a segment of the supply line through which this supply current flows. This supply line contains no additional components to facilitate the measuring of the voltage.

Figure 3

[illegible]